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Attorney Docket: 155/50324  
PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: SHINCHIRO YAGI

Serial No.: 09/914,044

Filed: AUGUST 22, 2001

Title: INSPECTION OBJECT SILICON WAFER FOR THE PURPOSE OF  
DETECTING CRYSTAL DEFECTS AND THE METHOD OF  
DETECTING THEREOF

CHANGE OF CORRESPONDENCE ADDRESS

**Box OED**

Commissioner for Patents  
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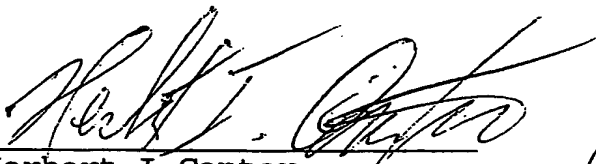
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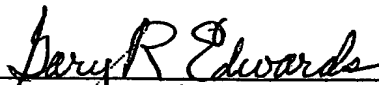
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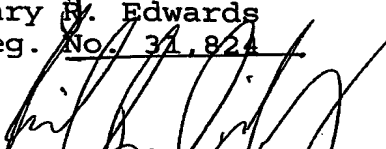
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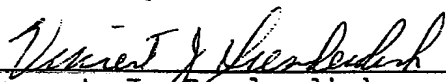
  
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Reg. No. 24,392


  
Donald D. Evenson  
Registration No. 26,160

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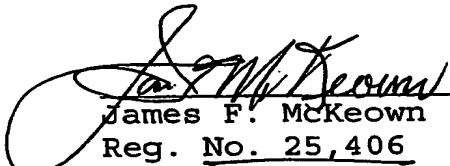
  
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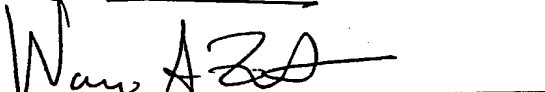
  
Karen Canaan  
Reg. No. 42,382


Respectfully submitted,


  
James F. McKeown  
Reg. No. 25,406

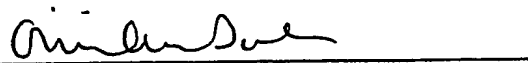
  
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Reg. No. 43,400

  
William G. Ackerman  
Reg. No. 45,320

  
Olivia A. Tolan  
Reg. No. 45,161

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